JEM-X: The X-ray monitor on INTEGRAL - DTU Orbit (08/08/2019)

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The INTEGRAL X-ray monitor, JEM-X, (together with the two gamma ray instruments, SPI and IBIS) will provide simultaneous imaging with arcminute angular resolution in the 3-60 keV band. The unique angular resolution and low energy response of JEM-X will play a crucial role in the detection and identification of gamma ray sources as well as in the analysis and scientific interpretation of the combined X-ray and gamma ray data. JEM-X is a coded aperture X-ray telescope consisting of two identical detectors. Each detector has a sensitive area of 500 cm(2), and views the sky (6.6 deg FOV, FWHM) through its own coded aperture mask. The coded cm masks are located 3.4 m above the detector windows. The detector field of view is constrained by X-ray collimators.

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